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ISA
67 Alexander Drive
P.O. Box 12277
Research Triangle Park, North Carolina 27709
Phone: 919-549-8411
Fax: 919-549-8288
E-mail: info@isa.org
ISA Online: <http://www.isa.org>

Proceedings Table of Contents

Analysis Division Symposium; AD 2007
Marriott Houston Hobby Airport; Houston, TX , USA; 15 – 19 April 2007

Session	Title / Author(s)	Page
AD2007.S01	SPECTROSCOPY: 1 <i>Bob Saltzman (Saltzman & Associates)</i>	
S01.1 (P025)	I Diode Array Process Analyzer for Sulfur Recovery Applications <i>Aaron Rollo, (Applied Analytics)</i>	1
S01.2 (P001)	A Single Analyzer / Sample System for the Determination of H ₂ S, COS (NDUV) and H ₂ (TCD) in a Refinery SRU Tail Gas Treating Unit (TGTU) <i>Kevin Harris, Phil Harris, Randy Hauer (AMETEK Process Instr.)</i>	13
AD2007.S02	GAS CHROMATOGRAPHY: 1 <i>Jerry Clemons (ABB Analytical Products)</i>	
S03.1 (P008)	On-line Analysis of Ethylene Furnace Liquid Feedstock <i>Rod Spittler, Andy Weber (The Dow Chemical Co.)</i>	25
S03.2 (P006)	Advances in Process GC Using MEMS Technology – Applications and Experiences with a Field-Mounted Device <i>Harald Mahler (Siemens AG, Germany)</i>	38
S03.3 (P004)	Alternative On-Line Hydrogen Measurement <i>Ulrich K. Gokeler (Siemens Energy & Automation)</i>	51
AD2007.S03	SPECTROSCOPY: 2 <i>Bob Saltzman (Saltzman & Associates)</i>	
S03.1 (P010)	New Process Gas Analyzer for the Measurement of Water Vapor Concentrations <i>A. Amerov, R. Fiore, M.Maskas, W. Meyer, K. Tran (Ametek Process Instr.)</i>	63
S03.2 (P017)	Diode Laser Sensors for Trace Moisture in Olefins Product Streams <i>X. Zhou, X. Liu, G. Sanger (SpectraSensors)</i>	75
S03.2 (P018)	Wavelength-Modulation Absorption Spectroscopy Based Trace Moisture Analyzer for Natural Gases <i>Sherry Liu, Xin Zhou, Greg Sanger (SpectraSensors)</i>	87
AD2007.S04	LIQUID CHROMATOGRAPHY <i>David Lewko (Bantrel)</i>	
S04.1 (P026)	Liquid Chromatography Based On-line Analyzers for Process Monitoring & Control <i>Rick Cooley, Mike Doyle (Dionex Corp.)</i>	99

Session	Title / Author(s)	Page
AD2007.S05	MARKETING <i>Dale Merriman (MTI Analytical Technology)</i>	
S05.1 (T023)	TUTORIAL: Process Analyzer Marketplace <i>Steve Walton, Terry McMahon (PAI Partners)</i>	109
AD2007.S06	VALIDATION: 1 <i>Dale Merriman (MTI Analytical Technology)</i>	
S06.1 (P029)	Preparing Trace Moisture Standards in Reactive Matrix Gases <i>Jim McKinley (Kin-Tek Laboratories)</i>	111
S06.2 (P030)	Adding Relative Humidity to Trace Concentration Gas Standards in a Permeation System <i>Danet Vrazel (Kin-Tek Laboratories)</i>	120
AD2007.S07	COMMUNICATIONS <i>Bob Farmer (Siemens)</i>	
S07.1 (P032)	Open Industrial Networks - Connecting to the Future <i>Ian Verhappen (MTL Instrument Group)</i>	130
AD2007.S08	SPECTROSCOPY:3 <i>Bob Saltzman (Saltzman & Associates)</i>	
S08.1 (P009)	Simultaneous Measurement of Ethane and Propane in a Methane Stream Using an EP-IR Based Hydrocarbon Analyzer <i>Bertrand Lanher (Aspectrics)</i>	134
S08.2 (P014)	Raman Process Analyzer for At-Line and Real-Time Measurement of Chemical Composition <i>Gordon Brown (Cambrius)</i>	146
AD2007.S09	OPTICAL TECHNIQUES <i>David Lewko (Bantrel)</i>	
S09.1 (P027)	In-Line Turbidity Measurements for Industrial Processes <i>David Bigalke, John Groetsch (Mettler-Toledo Ingold)</i>	158
AD2007.S10	VALIDATION: 2 <i>Dale Merriman (MTI Analytical Technology)</i>	
S10.1 (T022)	TUTORIAL: Assuring Traceable Accuracy of Trace Concentrations of Gas Standards <i>Jim McKinley (Kin-Tek Laboratories)</i>	168

Session	Title / Author(s)	Page
AD2007.S11	SAMPLING SYSTEMS: 1 <i>Bob Sherman(CIRCOR Tech)</i>	
S11.1 (P019)	The Importance of Training on Sample Handling & Conditioning <i>Mark Firmin (A+ Corp)</i>	182
AD2007.S12	EMERGING TECHNOLOGY <i>Rod Spitler (Dow Chemical)</i>	
S12.1 (P016)	Applications of Imaging Systems in Process Control and Optimization <i>Tod Canty, Keith DeMonstoy (Canty Process Technologies)</i>	189
S12.2 (P028)	An Ultra-Sensitive, Multi-Species Trace Gas Analyzer for Process Analysis and Control <i>Eric Crosson, Kathleen Hartnett (Picarro)</i>	N/A
S12.3 (P003)	Rapid On-Line Analysis of Acetylene for Hydrogenation Reactor Control Optimization <i>Linh Le, J.D. Tate, Mary Beth Seaholtz (Dow Chemical); Manish Gupta, Doug Baer (Los Gatos Research) Trevor Knittel, Alan Cowie, Jie Zhu (Analytical Specialties)</i>	198
S12.4 (P007)	Emerging Applications for Tunable Diode Laser - the Promise and the Problems <i>Trevor Knittle, Don Wyatt, Jie Zhu (Analytical Specialties); Linh Le, J.D. Tate (Dow Chemical)</i>	212
AD2007.S13	PANEL <i>Panel Members</i>	
S13.1 (T033)	Process Analyzer Systems - Levels of Acceptance Testing <i>David Lewko (Bantrel); Pete Wisneski (Chevron); Bac Vu (ExxonMobil)</i>	213
AD2007.S14	COMPOSITION ANALYSES <i>Ken Konrad (Intek Corp.)</i>	
S14.1 (P031)	Stack Sampling and Analysis for Total Composition <i>John Burkland, Jimmy Converse (TASC)</i>	214
AD2007.S15	SAMPLING SYSTEMS: 2 <i>Bob Sherman(CIRCOR Tech)</i>	
S15.1 (P021)	Hazardous Operation Sample Probe for Insertion/Retraction Under High Process Pressure Conditions <i>Don Mayeaux (A+ Corp.)</i>	224
S15.2 (P011)	Analysis of Gas Streams with High Dew Points on a Wet or Dry Basis	232

Session	Title / Author(s)	Page
	<i>Russel Ellis (Servomex)</i>	
AD2007.S16	MASS SPECTROMETRY <i>Jim Tatera (Tatera & Assoc.)</i>	
S16.1 (P015)	Optimizing Chemical Processes Using High Temperature Multi-Point Sampling Mass Spectrometry <i>Robert Wright, (Thermo Fisher Scientific, Winsford UK); Pete Traynor, (Thermo Fisher Scientific, Sugar Land, TX)</i>	239
AD2007.S17	X-RAY FLUORESCENCE <i>Jim Tatera (Tatera & Assoc.)</i>	
S17.1 (P012)	Direct Measurement of Low Level Chlorine in Crude Oil <i>Zewu Chen, Berry Beamer, Jay Burdett (XOS)</i>	249
AD2007.S18	SAMPLING SYSTEMS: 3 <i>Bob Sherman(CIRCOR Tech)</i>	
S18.1 (P013)	The Reality of NESSI - The Need for the Coexistence of Generation 1, Generation 1.V, and Generation 11 <i>Richard Ales, Douglas Nordstrom, David Simco (Swagelok)</i>	258
AD2007.S19	CALORIMETRY <i>Roy Muston (Shell Global Solutions)</i>	
S19.1 (P020)	Flare Gas and Recovery of Fuel Feed Gas Measurement with Residual Oxygen Calorimetry <i>David Hailey (Cosa Instrument Corp.)</i>	268
AD2007.S20	SYSTEMS <i>John Burkland (TASC)</i>	
S20.1 (P002)	Economics of Dependability for Analysis Systems <i>Herbert Hecht (SoHaR Inc.)</i>	276
AD2007.S21	GAS DETECTION <i>Mike Chaney (Equistar)</i>	
S21.1 (P034)	Laser Based Open Path Toxic Gas Detector <i>Gene Beebe (Honeywell Analytics)</i>	287